

**Search Notes**

Application/Control No.

10/775,983

Examiner

Ahshik Kim

Applicant(s)/Patent under  
Reexamination

MEIER ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	462.25	9/28/2005	AK
	462.26		
	462.24		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	9/28/2005	AK
Updated Search	5/26/2006	AK